Special Issue

Advanced RF/MM-Wave Circuits Design and Applications

Message from the Guest Editors

The rapid advancement in radio frequency (RF) and millimeter-wave (MM-Wave) technologies is pushing the boundaries of modern communication, sensing, and imaging systems. The growing demand for higher bandwidth, lower latency, and increased efficiency in applications such as 5G/6G wireless communications, radar systems, satellite communications, and autonomous vehicles necessitates innovative designs for RF/MM-Wave circuits and systems. This Special Issue aims to present the latest developments, trends, and applications in the design and implementation of advanced RF/MM-Wave circuits, focusing on novel materials, devices, and system architectures.

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